# MT4002N5

# N-Channel Enhancement Mode Field Effect Transistor

# **Product Summary**

- V<sub>DS</sub> = 40V
- I<sub>D</sub> = 60A (V<sub>GS</sub> = 10V)
- $R_{DS(ON)=3.1 \text{ m} \Omega} @V_{GS} = 10V$
- $R_{DS(ON)} = 3.5 m\Omega$  @V<sub>GS</sub> = 4.5V

## Features

- Advanced Trench Process Technology.
- · High Density Cell Design for Ultra Low On-Resistance.
- · Lead free product is acquired.
- RoHS Compliant.
- PDFN5x6-8L Package

## Applications

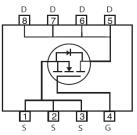
- · Portable Equipment and Battery Powered Systems.
- Power Management in Notebook Computers.

## Absolute Maximum Ratings (T<sub>A</sub> = 25<sup>°</sup>C unless otherwise noted)

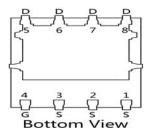


http://www.mtsemi.com

### Simplified Schematic



MARKING DIAGRAM & PIN ASSIGNMENT



Symbol	Parameter		Steady State	Units
V <sub>DS</sub>	Drain-Source Voltage		40	V
V <sub>GS</sub>	Gate-Source Voltage		±20	V
ID	Continuous Drain Current <sup>1</sup>		60	A
IDM	Pulsed Drain Current <sup>2</sup>	T <sub>C</sub> = 25℃	300	A
ls	Continuous Source Current (Diode Conduction) <sup>1</sup>		60	А
Eas	Single Pulse Drain-Source Avalanche Energy <sup>3</sup>		110	mJ
D-	Maximum Power Dissipation	T <sub>A</sub> = 25℃	2	w
PD		T <sub>C</sub> = 25℃	89	vv
TJ, TSTG	Operating Junction and Storage Temperature Range		-55~150	°C

Notes:

- 1. Surface Mounted on 1" x 1" FR4 Board, t  $\leq$  10 Sec.
- 2. Pulse width limited by maximum junction temperature.
- 3. The test condition is  $T_J$  =25  $^\circ\!\mathrm{C},~V_{DD}$  =30V,  $V_{GS}$  =10V, L=0.1mH, R\_G=25\Omega, I\_{AS} =50A.

# **Thermal Resistance Ratings**

Symbol	Parameter	Typical	Maximum	Unit
R <sub>thJA</sub>	Maximum Junction-to-Ambient	-	62.5	°C/W
RthJC	Maximum Junction-to-Case	-	1.4	C/VV

## Electrical Characteristics (T<sub>A</sub>=25°C, unless otherwise noted)

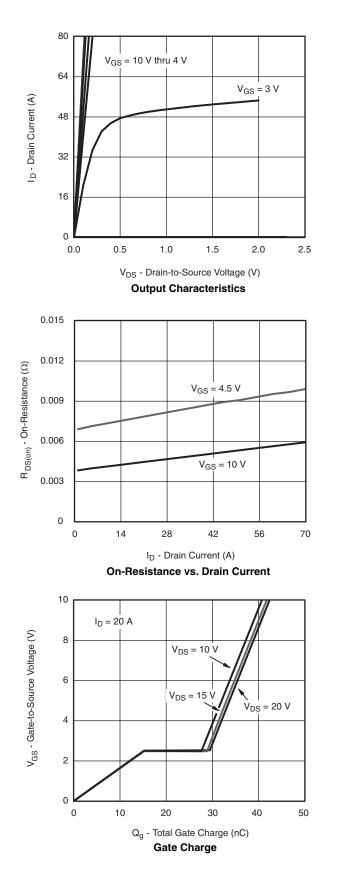
Symbol	Parameter	Test Condition	Min	Тур	Max	Unit	
Static Cl	haracteristics		I				
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA	40	-	-	V	
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1	1.4	2.2	V	
lgss	Gate-Body Leakage Current	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V	-	-	±100	nA	
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 32V, V <sub>GS</sub> = 0V -			1		
		$V_{DS}$ = 32V, $V_{GS}$ = 0V, $T_{J}$ = 85 $^{\circ}$ C	-		30	μA	
R <sub>DS(on)</sub>	Drain Source On State Resistance <sup>a</sup>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 60A	-	3.1	4.1	mΩ	
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 30A	-	3.5	4.5		
Vsd	Diode Forward Voltage <sup>a</sup>	V <sub>GS</sub> = 0V, I <sub>S</sub> = 40A	-	0.82	1.3	V	
Dynamic	Characteristics <sup>b</sup>						
Ciss	Input Capacitance		-	5120	-		
Coss	Output Capacitance	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 0V, f = 1MHz	-	1210	-	pF	
Crss	Reverse Transfer Capacitance		-	390	-		
Qg	Total Gate Charge		-	41	-		
Q <sub>gs</sub>	Gate-Source Charge	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A	-	15	-	nC	
Q <sub>gd</sub>	Gate-Drain Charge		-	12	-		
t <sub>d(on)</sub>	Turn-On Delay Time		-	22	-		
tr	Rise Time	V <sub>DD</sub> = 15V, V <sub>GS</sub> = 4.5V	-	35	-		
$t_{d(off)}$	Turn-Off Delay Time	I <sub>D</sub> = 20A, R <sub>GEN</sub> = 3Ω -		50	-	- nSec	
t <sub>f</sub>	Fall Time		-	27	-		
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =20A, di/dt= 100A/μA, T <sub>J</sub> =25°C	-	33	-	nSec	

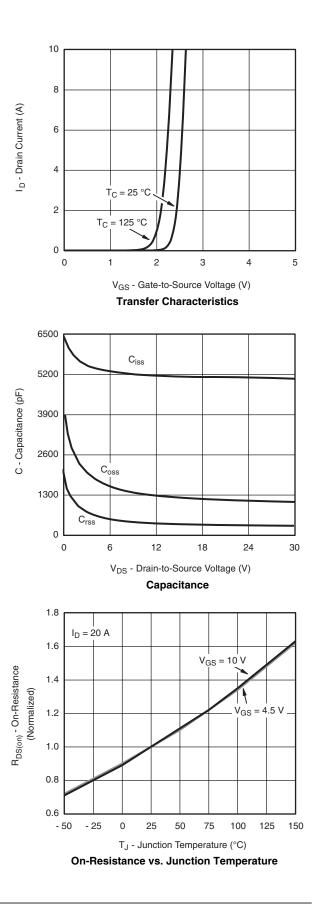
Note:

a. Pulse test; pulse width  $\leq$  300µs, duty cycle  $\leq$  2%.

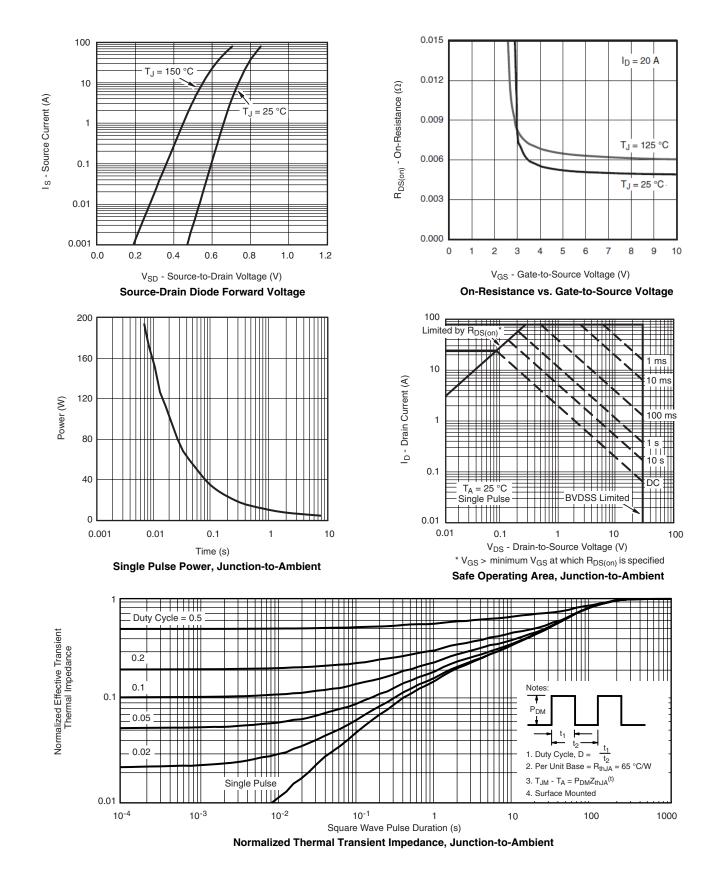
b. Guaranteed by design, not subject to production testing.

## **Characteristics Curve**





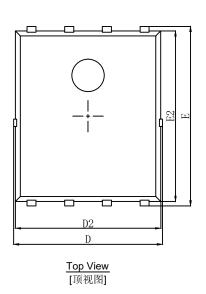
## **Characteristics Curve**



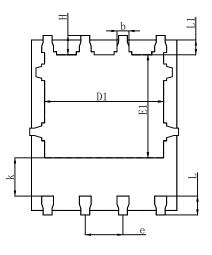
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PDFNWB5×6-8L(P1.27T0.95) PACKAGE OUTLINE DIMENSIONS

<u>4</u>3



<u>Side View</u> [侧视图]



<u>Bottom View</u> [背视图]

Sumbol	Dimensions In Millimeters		Dimensions In Inches	
Symbol	Min.	Max.	Min.	Max.
А	0.900	1.000	0.035	0.039
A3	0.254REF.		0.010REF.	
D	4.944	5.096	0.195	0.201
ш	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
е	1.270TYP.		0.050TYP.	
L	0.559	0.711	0.022	0.028
L1	0.424	0.576	0.017	0.023
Н	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°

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